

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at www.onsemi.com

Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild guestions@onsemi.com.

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officer



May 2015

FDPC5030SG

PowerTrench® Power Clip 30V Asymmetric Dual N-Channel MOSFET

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 5.0 m Ω at V_{GS} = 10 V, I_D = 17 A
- Max $r_{DS(on)}$ = 6.5 m Ω at V_{GS} = 4.5 V, I_D = 14 A

Q2: N-Channel

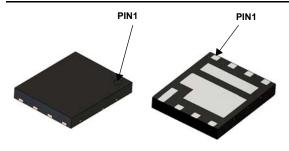
- Max $r_{DS(on)}$ = 2.4 m Ω at V_{GS} = 10 V, I_D = 25 A
- Max $r_{DS(on)}$ = 3.0 m Ω at V_{GS} = 4.5 V, I_D = 22 A
- Low Inductance Packaging Shortens Rise/Fall Times, Resulting in Lower Switching Losses
- MOSFET Integration Enables Optimum Layout for Lower Circuit Inductance and Reduced Switch Node Ringing
- RoHS Compliant

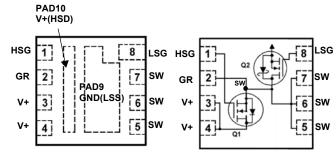
General Description

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous SyncFETTM (Q2) have been designed to provide optimal power efficiency.

Applications

- Computing
- Communications
- General Purpose Point of Load





Ton	Power Clin 5X6	Bottom

Pin	Name	Description	Pin	Name	e Description		Name	Description
1	HSG	High Side Gate	3,4,10	V+(HSD)	High Side Drain	8	LSG	Low Side Gate
2	GR	Gate Return	5,6,7	SW	Switching Node, Low Side Drain	9	GND(LSS)	Low Side Source

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted.

Symbol	Parameter		Q1	Q2	Units
V _{DS}	Drain to Source Voltage		30	30	V
V _{GS}	Gate to Source Voltage		±20	±12	V
	Drain Current -Continuous	T _C = 25 °C (Note 5)	56	84	
	-Continuous	T _C = 100 °C (Note 5)	35	53	
ID	-Continuous	T _A = 25 °C	17 ^{Note1a}	25 ^{Note1b}	A
	-Pulsed	T _A = 25 °C (Note 4)	227	503	
E _{AS}	Single Pulse Avalanche Energy	(Note 3)	54	96	mJ
	Power Dissipation for Single Operation	T _C = 25 °C		25	
P_{D}	Power Dissipation for Single Operation	T _A = 25 °C		2.3 ^{Note1b}	W
	Power Dissipation for Single Operation	T _A = 25 °C	1.0 ^{Note1c}	1.1 ^{Note1d}	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to	+150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	5.6	4.9	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	60 ^{Note1a}	55 ^{Note1b}	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	130 ^{Note1c}	120 ^{Note1d}	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDPC5030SG	FDPC5030SG	Power Clip 56	13 "	12 mm	3000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted.

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Chara	acteristics						
D\/	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	Q1	30			V
BV_{DSS}	Drain to Source Breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	Q2	30			V
ΔBV _{DSS}	Breakdown Voltage Temperature	I _D = 250 μA, referenced to 25 °C	Q1		15		mV/°C
ΔT_{J}	Coefficient	I_D = 10 mA, referenced to 25 °C	Q2		16		IIIV/ C
	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V	Q1			1	μΑ
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$	Q2			500	μΑ
1	Gate to Source Leakage Current,	V _{GS} = 20 V, V _{DS} = 0 V V _{GS} = 12 V, V _{DS} = 0 V	Q1			100	nA
I _{GSS}	Forward	$V_{GS} = 12 \text{ V}, V_{DS} = 0 \text{ V}$	Q2			100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$ $V_{GS} = V_{DS}, I_D = 1 mA$	Q1 Q2	1.0 1.0	1.7 1.6	3.0 3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C I_D = 10 mA, referenced to 25 °C	Q1 Q2		-5 -3		mV/°C
-	Drain to Source On Resistance	V _{GS} = 10V, I _D = 17 A V _{GS} = 4.5 V, I _D = 14 A V _{GS} = 10 V, I _D = 17 A,T _J =125 °C	Q1		4.1 5.4 5.7	5.0 6.5 7.0	mΩ
r _{DS(on)}	Drain to Source On Resistance	V _{GS} = 10V, I _D = 25 A V _{GS} = 4.5 V, I _D = 22 A V _{GS} = 10 V, I _D = 25 A ,T _J =125 °C	Q2		1.9 2.4 2.7	2.4 3.0 3.4	1115.2
9 _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 17 \text{ A}$ $V_{DS} = 5 \text{ V}, I_{D} = 25 \text{ A}$	Q1 Q2		93 139		S

Dynamic Characteristics

C _{iss}	Input Capacitance	Q1:	Q1 Q2		1224 2730	1715 3825	pF
C _{oss}	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$ $Q2:$	Q1 Q2		397 801	560 1125	pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2		42 72	60 100	pF
R _g	Gate Resistance		Q1 Q2	0.1 0.1	0.5 1.1	1.5 2.2	Ω

Switching Characteristics

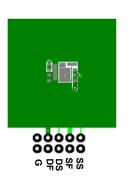
t _{d(on)}	Turn-On Delay Time			Q1 Q2	8 10	16 19	ns
t _r	Rise Time	Q1: V _{DD} = 15 V, I _D = 17	7 A, R _{GEN} = 6 Ω	Q1 Q2	2	10 10	ns
t _{d(off)}	Turn-Off Delay Time	Q2:	5 A Rosu = 6 O	Q1 Q2	18 30	33 48	ns
t _f	Fall Time	VDD - 13 V, 10 - 20	V_{DD} = 15 V, I_{D} = 25 A, R_{GEN} = 6 Ω		2	10 10	ns
Qg	Total Gate Charge	V _{GS} = 0 V to 10 V	Q1	Q1 Q2	17 39	24 55	nC
Qg	Total Gate Charge	V _{GS} = 0 V to 4.5 V		Q1 Q2	8 18	11 26	nC
Q _{gs}	Gate to Source Gate Charge		Q2 V _{DD} = 15 V, I _D	Q1 Q2	3.1 6.1		nC
Q _{gd}	Gate to Drain "Miller" Charge		= 25 A	Q1 Q2	2.0 4.3		nC

Electrical Characteristics T_J = 25 °C unless otherwise noted.

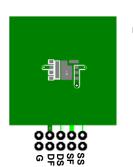
Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Drain-Sou	rce Diode Characteristics						
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 17 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = 25 \text{ A}$ (Note 2)	Q1		8.0	1.2	V
V SD	Source to Drain Blode I of Ward Voltage	$V_{GS} = 0 \text{ V}, I_S = 25 \text{ A}$ (Note 2)	Q2		8.0	1.2	V
+	Reverse Recovery Time	Q1	Q1		23	37	ns
۲rr	Reverse Recovery Time	I _F = 17 A, di/dt = 100 A/μs	Q2		27	44	115
0	Reverse Recovery Charge	Q2	Q1		8	16	nC
Q_{rr}	Reverse Recovery Charge	$I_F = 25 \text{ A}, \text{ di/dt} = 230 \text{ A/}\mu\text{s}$	Q2		31	50	110

Notes:

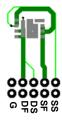
 $1.R_{\theta JA} \text{ is determined with the device mounted on a 1 in}^2 \text{ pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material, } R_{\theta CA} \text{ is determined by the user's board design.}$



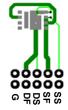
a. 60 °C/W when mounted on a 1 in² pad of 2 oz copper



b. 55 °C/W when mounted on a 1 in² pad of 2 oz copper



c. 130 °C/W when mounted on a minimum pad of 2 oz copper



d. 120 °C/W when mounted on a minimum pad of 2 oz copper

- 2 Pulse Test: Pulse Width < 300 $\mu\text{s},$ Duty cycle < 2.0%.
- 3. Q1 :E_{AS} of 54 mJ is based on starting T_J = 25 o C; L = 3 mH, I_{AS} = 6 A, V_{DD} = 30 V, V_{GS} = 10 V. 100% tested at L = 0.1 mH, I_{AS} = 20 A. Q2: E_{AS} of 96 mJ is based on starting T_J = 25 o C; L = 3 mH, I_{AS} = 8 A, V_{DD} = 30 V, V_{GS} = 10 V. 100% tested at L = 0.1 mH, I_{AS} = 27 A.
- 4. Pulsed Id refer to Fig.11 and Fig.24 SOA curve for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted.

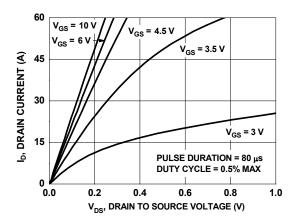


Figure 1. On Region Characteristics

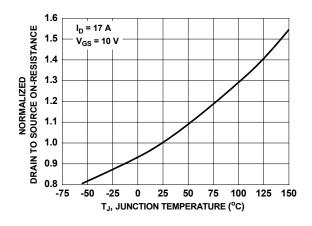


Figure 3. Normalized On Resistance vs. Junction Temperature

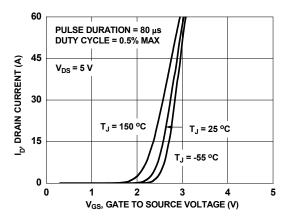


Figure 5. Transfer Characteristics

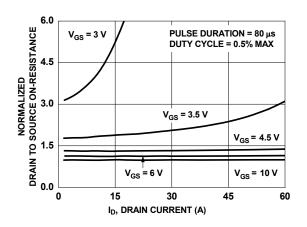


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

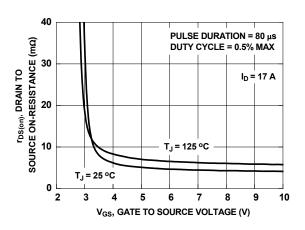


Figure 4. On-Resistance vs. Gate to Source Voltage

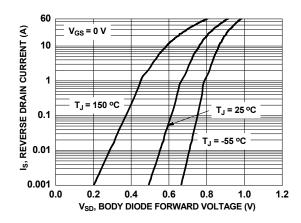


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted.

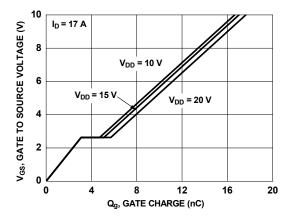


Figure 7. Gate Charge Characteristics

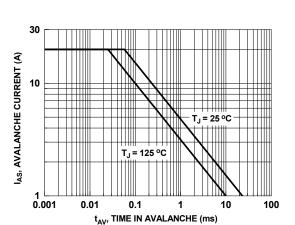


Figure 9. Unclamped Inductive Switching Capability

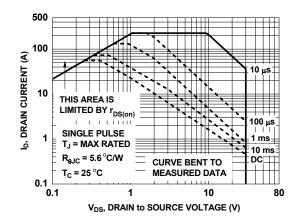


Figure 11. Forward Bias Safe Operating Area

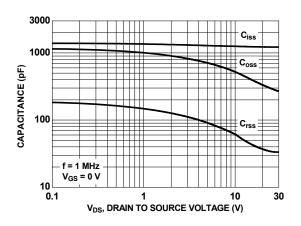


Figure 8. Capacitance vs. Drain to Source Voltage

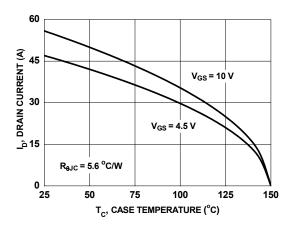


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

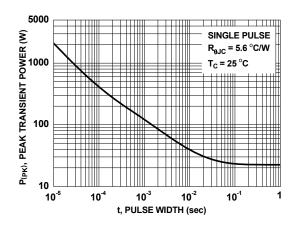


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted.

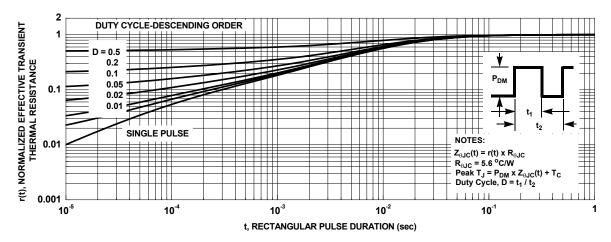


Figure 13. Junction-to-Case Transient Thermal Response Curve

Typical Characteristics (Q2 N-Channel) T_J = 25 °C unless otherwise noted.

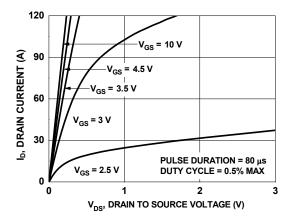


Figure 14. On- Region Characteristics

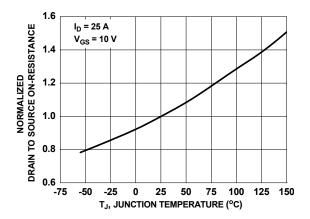


Figure 16. Normalized On-Resistance vs. Junction Temperature

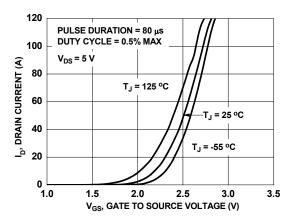


Figure 18. Transfer Characteristics

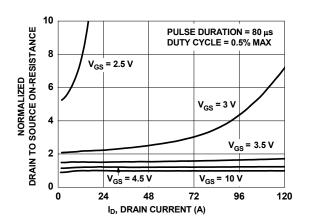


Figure 15. Normalized on-Resistance vs. Drain Current and Gate Voltage

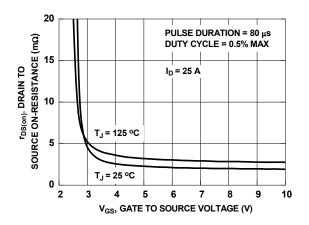


Figure 17. On-Resistance vs. Gate to Source Voltage

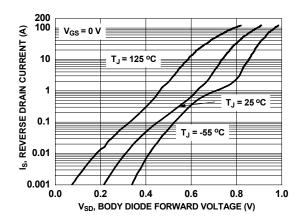


Figure 19. Source to Drain Diode Forward Voltage vs. Source Current

Typical Characteristics (Q2 N-Channel) T_{.I} = 25°C unless otherwise noted.

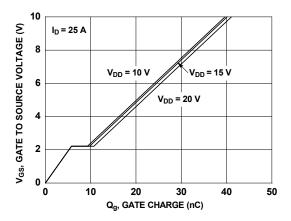


Figure 20. Gate Charge Characteristics

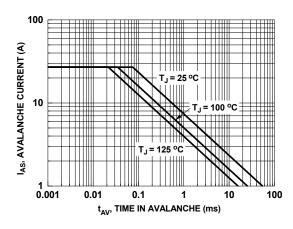


Figure 22. Unclamped Inductive Switching Capability

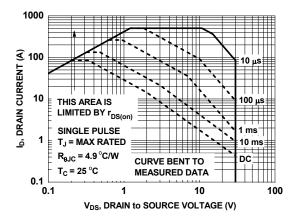


Figure 24. Forward Bias Safe Operating Area

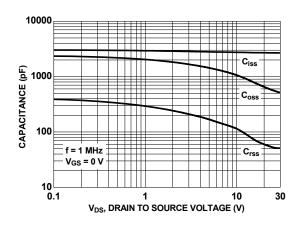


Figure 21. Capacitance vs. Drain to Source Voltage

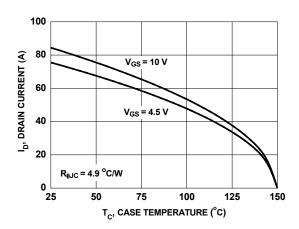


Figure 23. Maximum Continuous Drain Current vs. Case Temperature

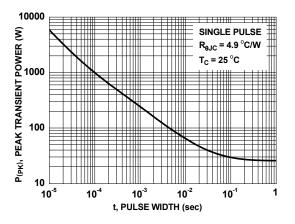


Figure 25. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 N-Channel) T_J = 25 °C unless otherwise noted.

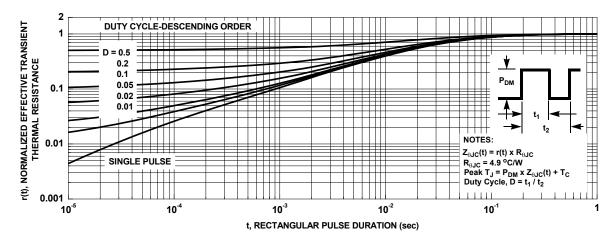


Figure 26. Junction-to-Case Transient Thermal Response Curve

Typical Characteristics (continued)

SyncFETTM Schottky Body Diode Characteristics

Fairchild's SyncFETTM process embeds a Schottky diode in parallel with PowerTrench[®] MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 27 shows the reverse recovery characteristic of the FDPC5030SG.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

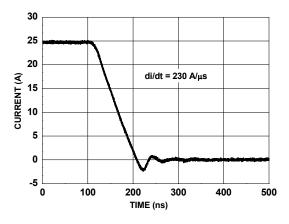


Figure 27. FDPC5030SG SyncFETTM Body Diode Reverse Recovery Characteristic

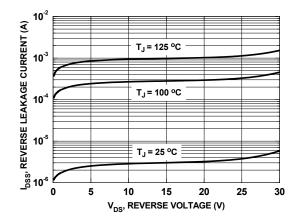
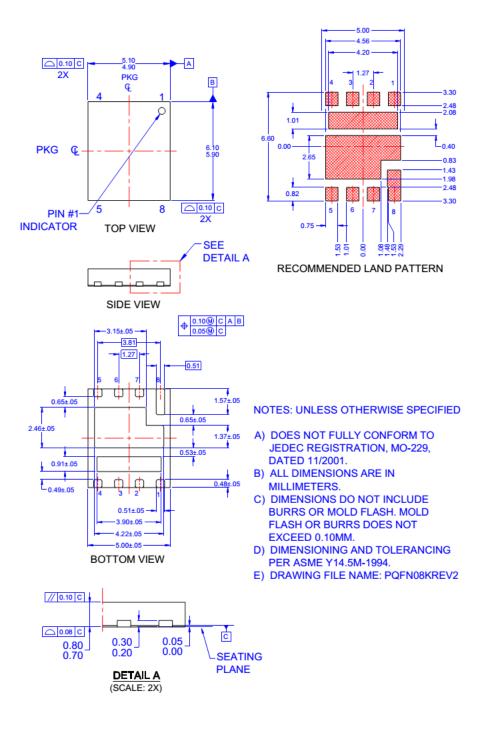


Figure 28. SyncFETTM Body Diode Reverse Leakage vs. Drain-Source Voltage

Dimensional Outline and Pad Layout



Package drawings are provided as a service to customers considering Fairchild components. Drawings may change in any manner without notice. Please note the revision and/or date on the drawing and contact a Fairchild Semiconductor representative to verify or obtain the most recent revision. Package specifications do not expand the terms of Fairchild's worldwide terms and conditions, specifically the warranty therein, which covers Fairchild products.





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

AccuPower™ AttitudeEngine™ Awinda[®] AX-CAP®* BitSiC™ Build it Now™ CorePLUS™ CorePOWER™ CROSSVOLT™

Current Transfer Logic™ DEUXPEED® Dual Cool™ EcoSPARK® EfficentMax™ ESBC™

Fairchild® Fairchild Semiconductor® FACT Quiet Series™ FACT® FAST® FastvCore™ FETBench™

F-PFS™ FRFET®

Global Power ResourceSM GreenBridge™ Green FPS™

Green FPS™ e-Series™ Gmax™ GTO™ IntelliMAX™ ISOPLANAR™

Marking Small Speakers Sound Louder and Better™

MegaBuck™ MICROCOUPLER™ MicroFET™ MicroPak™ MicroPak2™ MillerDrive™ MotionMax™ MotionGrid[®]

MTi[®] MTx[®] MVN® mWSaver® OptoHiT™ OPTOLOGIC® OPTOPLANAR®

Power Supply_WebDesigner™

PowerTrench® PowerXS™

Programmable Active Droop™

OFET® QS™ Quiet Series™

RapidConfigure™

Saving our world, 1mW/W/kW at a time™ SignalWise™ SmartMax™ SMART START™

Solutions for Your Success™

SPM STEALTH™ $\mathsf{SuperFET}^{\circledR}$ SuperSOT™-3 SuperSOT™-6 . SuperSOT™-8 SupreMOS[®] SyncFET™ Sync-Lock™

SYSTEM ®* TinyBoost® TinyBuck[®] TinyCalc™ TinyLogic[®]
TINYOPTO™ TinyPower™ TinyPWM™ TinyWire™ TranSiC™ TriFault Detect™ TRUECURRENT®*

UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ VoltagePlus™ XS™ Xsens™ 仙童 ™

μSerDes™

*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

FPS™

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. TO OBTAIN THE LATEST, MOST UP-TO-DATE DATASHEET AND PRODUCT INFORMATION, VISIT OUR WEBSITE AT http://www.fairchildsemi.com. Fairchild does not assume any liability arising out of the application or use of ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.
		Pov 174

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdt/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and exp

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support:
Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

ON Semiconductor: FDPC5030SG